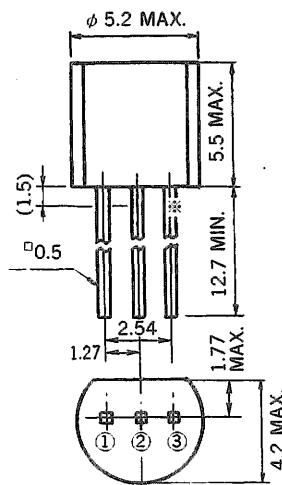


0.8 A MOLD TRIAC**PACKAGE DIMENSIONS**
(Unit : mm)**PIN CONNECTION**

1. T₁ Terminal
 2. Gate
 3. T₂ Terminal
- ※ Measure point of Case Temperature

DESCRIPTION

The AC0V8DGM is all diffused type TRIAC granted RMS On-state Current 0.8 Amps, with rated voltages up to 400 volts.

This is designed specifically to be driven by low-level logic in any gating mode.

FEATURES

- The AC0V8DGM offers sensitive gate specs of 5 and 10 mA, in all four quadrants.
- You can fill the gap between microprocessor controls and the power-output requirements.
- This is housed in the popular TO-92 package.
- The package features excellent environmental stress and temperature cycling.

APPLICATIONS

Solid-state relays, microprocessor interfacing, TTL logic and various solid-state switch designs alone or with larger TRIAC.

MAXIMUM RATINGS

| ITEM | SYMBOL | MAXIMUM RATINGS | UNIT | NOTE |
|---------------------------------|---|------------------------------|------------------|-------------|
| Repetitive Peak off Voltage | V _{DRM} | 400 | V | |
| Non-repetitive Peak off Voltage | V _{DSDM} | 500 | V | |
| RMS On-State Current | I _{T(RMS)} | 0.8 (T _c = 68 °C) | A | Fig. 12, 13 |
| Peak Surge On-State Current | I _{TSM} | 7 (50 Hz), 8 (60 Hz) | A | Fig. 2 |
| Fusing Current | J _f ² T _{dt} | 0.2 (1 ms ≤ t ≤ 10 ms) | A ² s | |
| Peak Gate Power Dissipation | P _{GM} | 1 | W | |
| Average Gate Power Dissipation | P _{G(AV)} | 0.1 | W | |
| Peak Gate Current | I _{GM} | ±1 | A | |
| Junction Temperature | T _j | 125 | °C | |
| Storage Temperature | T _{stg} | -55 to +150 | °C | |

ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$)

| ITEM | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT | NOTE | |
|--|---------------|--|---|-------------------------------|------|------|------------------------|-------------|--|
| Peak Off-State Current | I_{DRM} | $V_{DM} = V_{DRM}$ | $T_j = 25^\circ\text{C}$ | — | — | 10 | μA | | |
| | | | $T_j = 125^\circ\text{C}$ | — | — | 100 | | | |
| On-State Voltage | V_{TM} | $I_{TM} = 1.2 \text{ A}$ | | — | — | 1.5 | V | Fig. 1 | |
| Critical Rate of Rise of Off-State Voltage | dv/dt | $T_j = 125^\circ\text{C}, V_{DM} = \frac{2}{3} V_{DRM}$ Gate Open Circuited Exponential Waveform | | — | 50 | — | $\text{V}/\mu\text{s}$ | | |
| *DC Gate Trigger Current | MODE I | I_{GT} | $V_{DM} = 12 \text{ V}$ $R_L = 100 \Omega$ | G; Positive, T_2 ; Positive | — | — | 5 | | |
| | II | | | G; Negative, T_2 ; Positive | — | — | 10 | mA | |
| | III | | | G; Negative, T_2 ; Negative | — | — | 5 | | |
| | IV | | | G; Positive, T_2 ; Negative | — | — | 10 | | |
| DC Gate Trigger Voltage | MODE I | V_{GT} | $V_{DM} = 12 \text{ V}$ $R_L = 100 \Omega$ | G; Positive, T_2 ; Positive | — | — | 1.0 | V | |
| | II | | | G; Negative, T_2 ; Positive | — | — | 1.5 | | |
| | III | | | G; Negative, T_2 ; Negative | — | — | 1.0 | | |
| | IV | | | G; Positive, T_2 ; Negative | — | — | 1.5 | | |
| Gate Non-Trigger Voltage | V_{GD} | $T_j = 125^\circ\text{C}$ $V_{DM} = \frac{1}{2} V_{DRM}$ | | 0.1 | — | — | V | | |
| DC Holding Current | I_H | $V_D = 24 \text{ V}, I_{TM} = 1 \text{ A}$ | | — | 5 | 10 | mA | | |
| Critical Rate of Rise of Commutating Off-State Voltage | $(dv/dt)_c$ | $T_j = 125^\circ\text{C}, I_{TM} = 1.2 \text{ A}$ $(di_T/dt)_c = -0.5 \text{ A/ms}$ $V_{DM} = 400 \text{ V}$ | | 1 | — | — | $\text{V}/\mu\text{s}$ | | |
| Steady State | $R_{th(j-c)}$ | Junction to Case | | — | — | 65 | $^\circ\text{C/W}$ | | |
| Thermal Resistance | $R_{th(j-a)}$ | Junction to Ambient | | — | — | 200 | $^\circ\text{C/W}$ | Fig. 14 | |

* All four quadrants: 5 mA Max. Selected types available from factory.

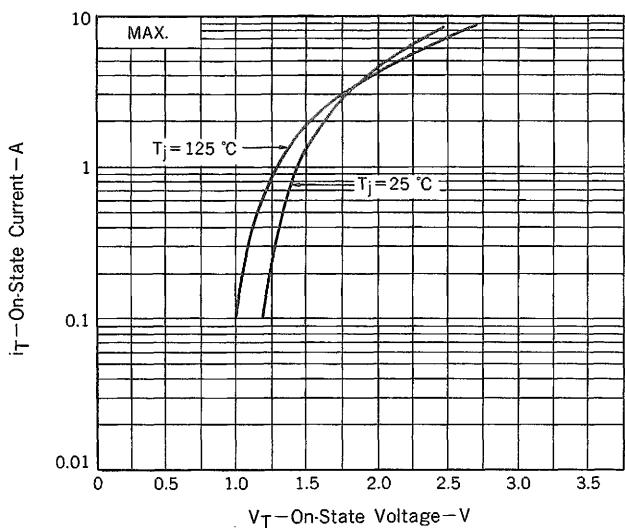
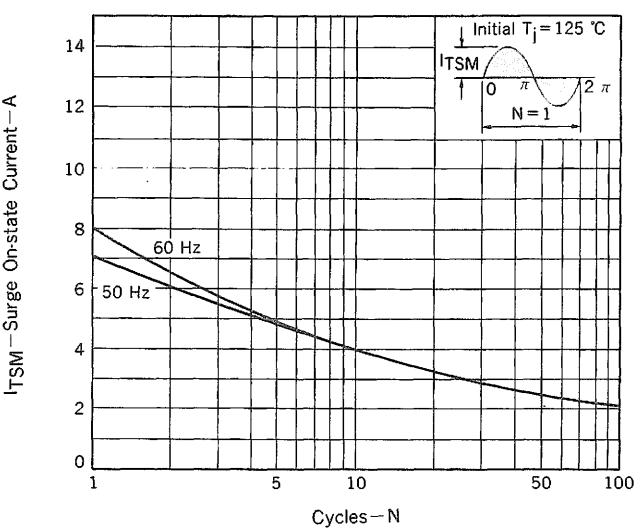
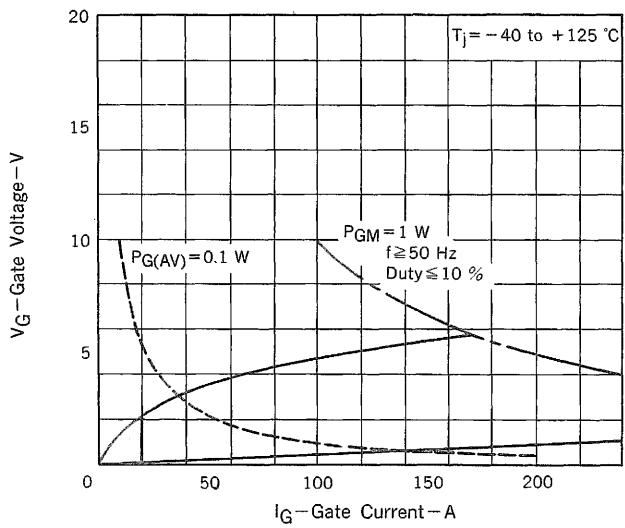
Fig. 1 $i_T - V_T$ CHARACTERISTICFig. 2 I_{TSM} RATINGFig. 3 $V_G - I_G$ RATING

Fig. 4 GATE CHARACTERISTIC

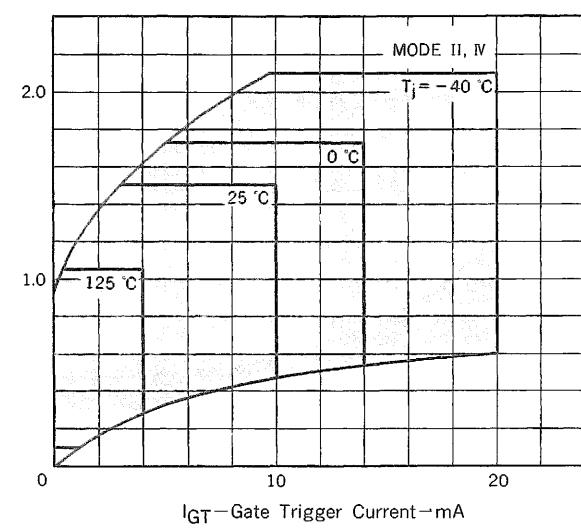


Fig. 5 GATE CHARACTERISTIC

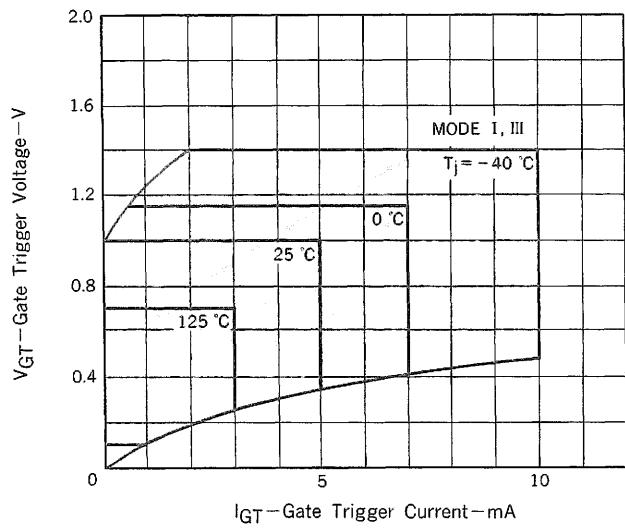
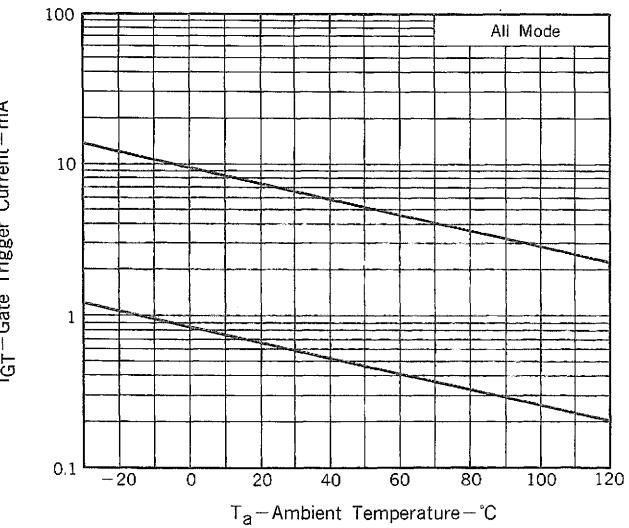
Fig. 6 $I_{GT} - T_a$ TYPICAL DISTRIBUTION

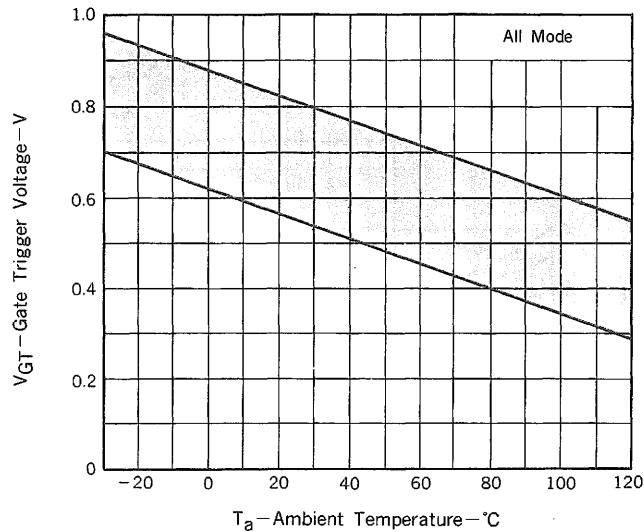
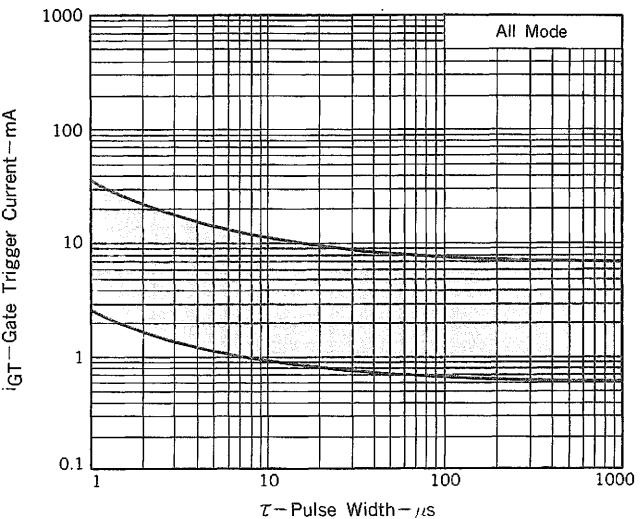
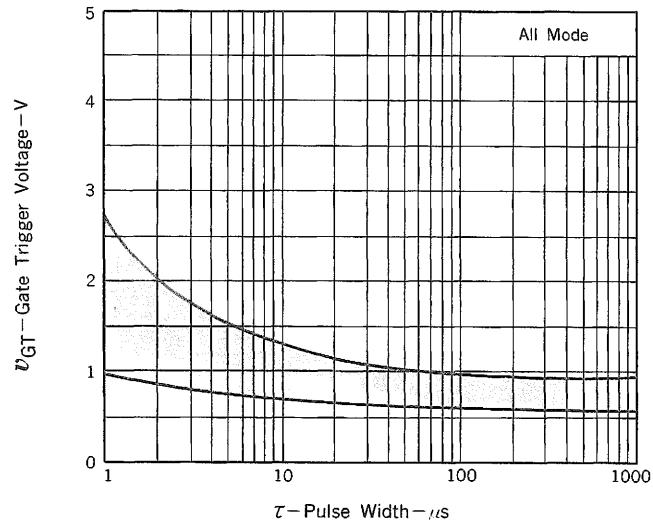
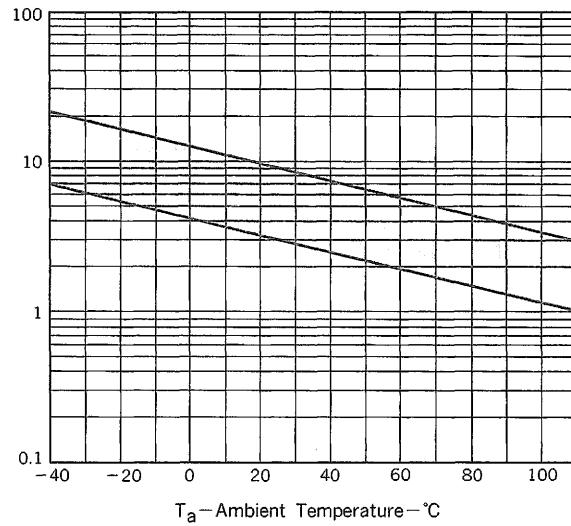
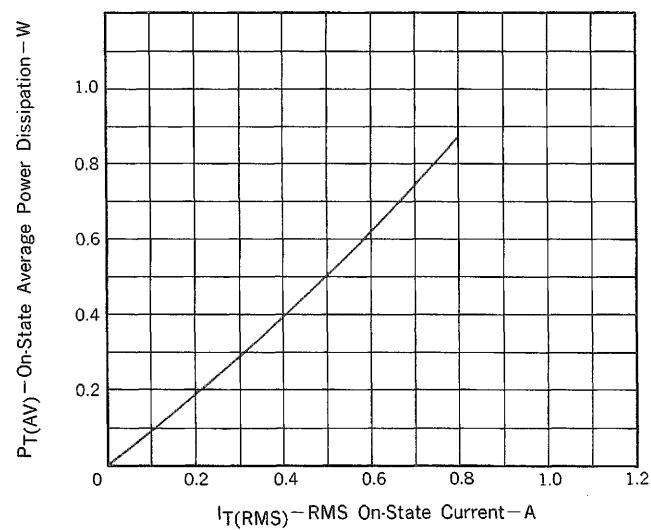
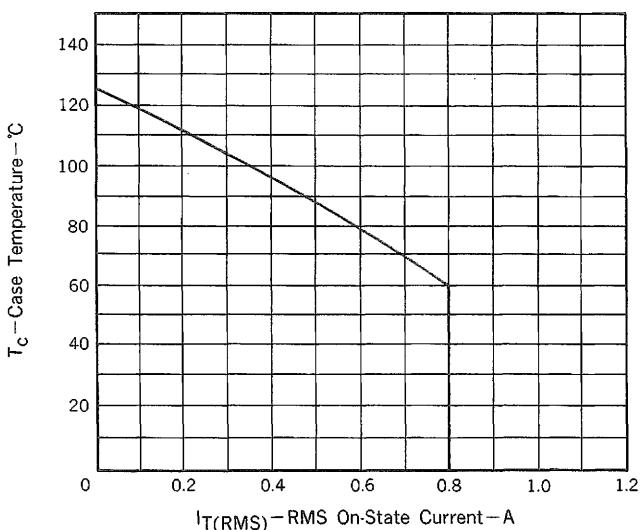
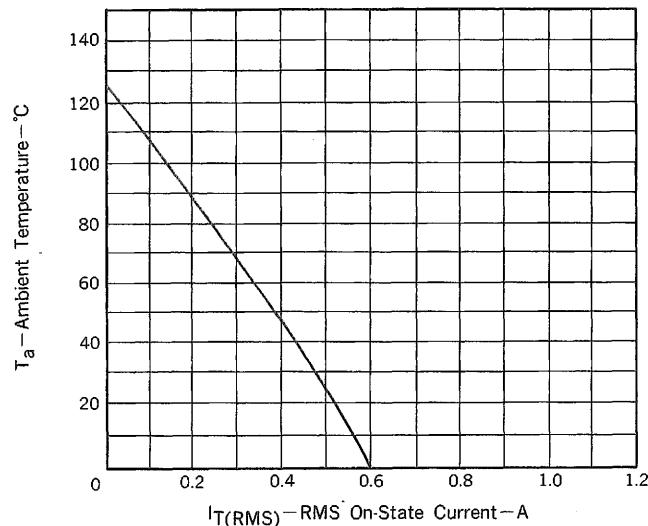
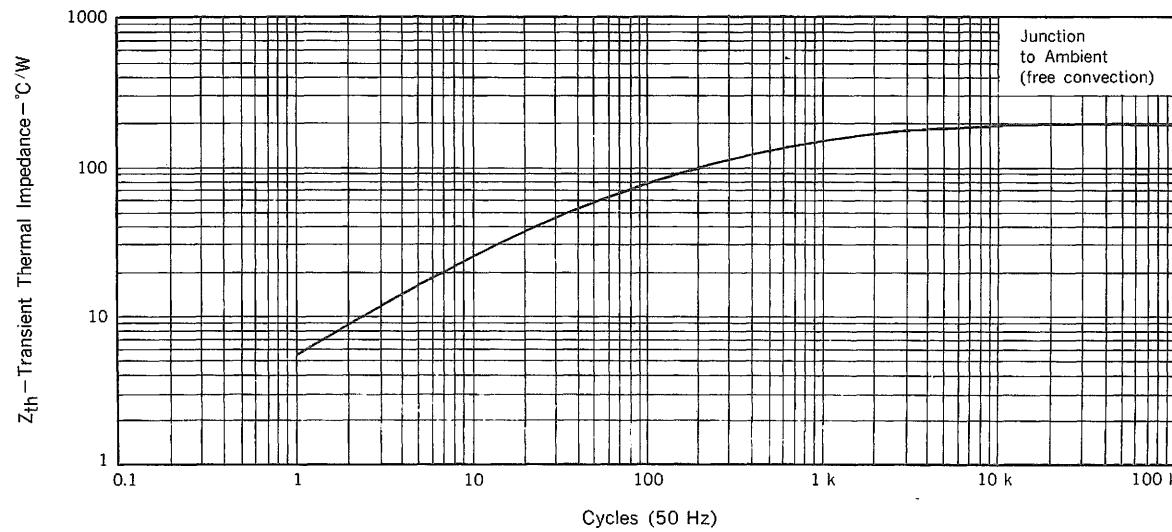
Fig. 7 $V_{GT} - T_a$ TYPICAL DISTRIBUTIONFig. 8 $i_{GT} - \tau$ TYPICAL DISTRIBUTIONFig. 9 $v_{GT} - \tau$ TYPICAL DISTRIBUTIONFig. 10 $i_H - T_a$ TYPICAL DISTRIBUTIONFig. 11 $P_{T(AV)} - I_{T(RMS)}$ CHARACTERISTICFig. 12 $T_c - I_{T(RMS)}$ RATING

Fig. 13 $T_a - I_{T(RMS)}$ RATINGFig. 14 Z_{th} CHARACTERISTIC

AC0V8DGM

NEC ELECTRON DEVICE